SDAS055E - APRIL 1982 - REVISED JULY 1996

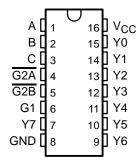
- Designed Specifically for High-Speed Memory Decoders and Data Transmission Systems
- Incorporate Three Enable Inputs to Simplify Cascading and/or Data Reception
- Package Options Include Plastic Small-Outline (D) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

description

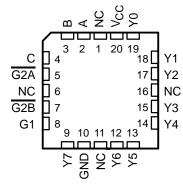
The 'ALS138A and 'AS138 are 3-line to 8-line decoders/demultiplexers designed for highperformance memory-decoding or data-routing applications requiring very short propagation delay times. In high-performance systems, these devices can be used to minimize the effects of decoding. When employed system high-speed memories with a fast enable circuit, the delay times of the decoder and the enable time of the memory are usually less than the typical access time of the memory. The effective system delay introduced by the Schottky-clamped system decoder is negligible.

The conditions at the binary-select (A, B, and C) inputs and the three enable (G1, G2A, and G2B) inputs select one of eight output lines. Two active-low and one active-high enable inputs

SN54ALS138A, SN54AS138 . . . J PACKAGE SN74ALS138A, SN74AS138 . . . D OR N PACKAGE (TOP VIEW)



SN54ALS138A, SN54AS138 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

reduce the need for external gates or inverters when expanding. A 24-line decoder can be implemented without external inverters and a 32-line decoder requires only one inverter. An enable input can be used as a data input for demultiplexing applications.

The SN54ALS138A and SN54AS138 are characterized for operation over the full military temperature range of –55°C to 125°C. The SN74ALS138A and SN74AS138 are characterized for operation from 0°C to 70°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

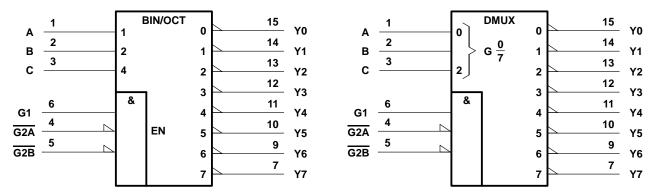


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FUNCTION TABLE

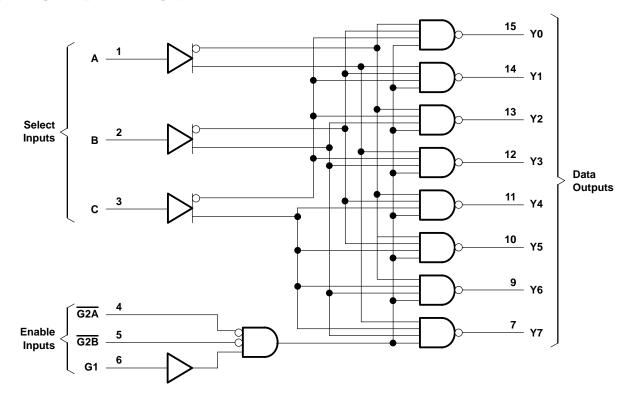
INPUTS								OUT	DUTE				
ENABLE SELECT					OUTPUTS								
G1	G2A	G2B	С	В	Α	Y0	Y 1	Y2	Y3	Y4	Y5	Y6	Y7
Х	Н	Х	Х	Х	Х	Н	Н	Н	Н	Н	Н	Н	Н
Х	X	Н	Х	Χ	Χ	Н	Н	Н	Н	Н	Н	Н	Н
L	X	X	Х	Χ	X	Н	Н	Н	Н	Н	Н	Н	Н
Н	L	L	L	L	L	L	Н	Н	Н	Н	Н	Н	Н
Н	L	L	L	L	Н	Н	L	Н	Н	Н	Н	Н	Н
Н	L	L	L	Н	L	Н	Н	L	Н	Н	Н	Н	Н
Н	L	L	L	Н	Н	Н	Н	Н	L	Н	Н	Н	Н
Н	L	L	Н	L	L	Н	Н	Н	Н	L	Н	Н	Н
Н	L	L	Н	L	Н	Н	Н	Н	Н	Н	L	Н	Н
Н	L	L	Н	Н	L	Н	Н	Н	Н	Н	Н	L	Н
Н	L	L	Н	Н	Н	Н	Н	Н	Н	Н	Н	Н	L

logic symbols (alternatives)†



[†] These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, J, and N packages.

logic diagram (positive logic)



Pin numbers shown are for the D, J, and N packages.

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

recommended operating conditions

		SNS	4ALS13	8A	SN74ALS138A			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2			2			V
VIL	Low-level input voltage			0.7			8.0	V
IOH	High-level output current			-0.4			-0.4	mA
lOL	Low-level output current			4			8	mA
T _A	Operating free-air temperature	-55		125	0	-	70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST	CONDITIONS	SN54ALS138A SN74ALS138A		8A	UNIT			
PARAMETER	TEST	CONDITIONS	MIN TYP [‡] MAX MIN TYP [‡] MA			MAX	UNIT		
VIK	$V_{CC} = 4.5 \text{ V},$	I _I = –18 mA			-1.5			-1.5	V
Voн	$V_{CC} = 4.5 \text{ V},$	$I_{OH} = -0.4 \text{ mA}$	V _{CC} -2	2		V _{CC} -2	?		V
\/o.	V00 - 45 V	I _{OL} = 4 mA		0.25	0.4		0.25	0.4	V
VOL	V _{CC} = 4.5 V	$I_{OL} = 8 \text{ mA}$					0.35	0.5	V
lį	$V_{CC} = 5.5 \text{ V},$	V _I = 7 V			0.1			0.1	mA
lн	$V_{CC} = 5.5 \text{ V},$	V _I = 2.7 V			20			20	μΑ
I _{IL}	$V_{CC} = 5.5 \text{ V},$	V _I = 0.4 V			-0.1			-0.1	mA
ΙΟ§	$V_{CC} = 5.5 \text{ V},$	V _O = 2.25 V	-20		-112	-30		-112	mA
Icc	V _{CC} = 5.5 V			5	10		5	10	mA

[‡] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _C (C _L : R _L : T _A :		UNIT		
	, ,	, ,	SN54AL	S138A	SN74AL	S138A	
			MIN	MAX	MIN	MAX	
t _{PLH}	A D C	Amy V	2	28	5	22	ns
^t PHL	A, B, C	Any Y	6	22	6	18	115
^t PLH	G or G	Any Y	2	22	3	17	ns
^t PHL	9019	Ally I	4	21	4	17	115

 $[\]P$ For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

[§] The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC}	7 \
Input voltage, V _I	7 \
Operating free-air temperature range, T _A : SN54AS138	-55°C to 125°C
SN74AS138	0°C to 70°C
Storage temperature range, T _{stg}	−65°C to 150°C

recommended operating conditions

		SI	SN54AS138 SN74AS138		8	UNIT		
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
V_{IH}	High-level input voltage	2			2			V
V_{IL}	Low-level input voltage			0.8			0.8	V
ІОН	High-level output current			-2			-2	mA
loL	Low-level output current			20			20	mA
TA	Operating free-air temperature	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	TEST C	SN	SN54AS138			SN74AS138			
PARAMETER	TEST C	ONDITIONS	MIN	TYP [‡]	MAX	MIN	TYP [‡]	MAX	UNIT
VIK	$V_{CC} = 4.5 \text{ V},$	$I_{I} = -18 \text{ mA}$			-1.2			-1.2	V
Voн	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -2 \text{ mA}$	V _{CC} -2)		VCC -2	2		V
V_{OL}	$V_{CC} = 4.5 \text{ V},$	$I_{OL} = 20 \text{ mA}$		0.35	0.5		0.35	0.5	V
lj	$V_{CC} = 5.5 V$,	V _I = 7 V			0.1			0.1	mA
lН	$V_{CC} = 5.5 V$,	V _I = 2.7 V			20			20	μΑ
I _Ι L	$V_{CC} = 5.5 V,$	V _I = 0.4 V			-0.5			-0.5	mA
ΙΟ [§]	$V_{CC} = 5.5 V$,	V _O = 2.25 V	-30		-112	-30		-112	mA
IССН	V _{CC} = 5.5 V			12	17.5		12	17.5	mA
ICCL	V _{CC} = 5.5 V			14	20		14	20	mA

[‡] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.



[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

[§] The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

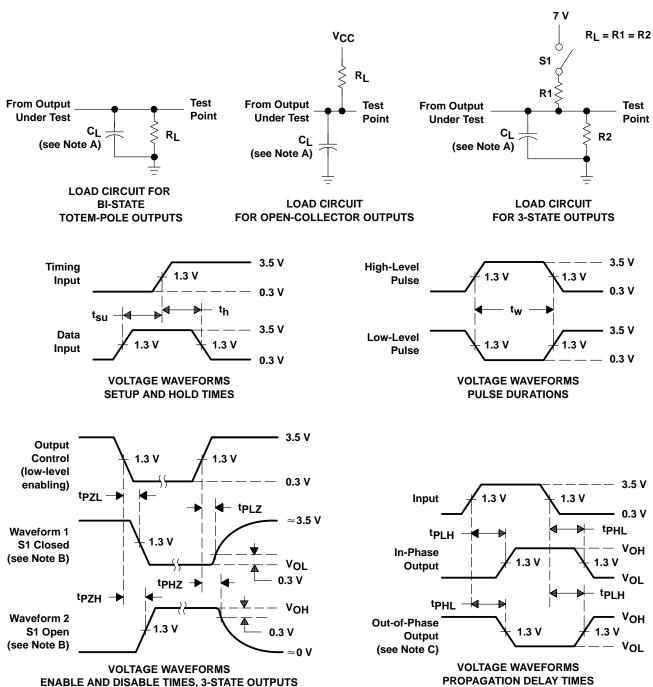
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switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _C C _L R _L T _A	UNIT			
		,	SN54A	\S138	SN74A	S138	0 ns
			MIN	MAX	MIN	MAX	
t _{PLH}	A, B, C	Any Y	2	11	2	10	ns
^t PHL			2	11	2	9.5	
tpLH	G1	Any V	2	11.5	2	10	20
^t PHL	5	Any Y	2	11	2	10	115
t _{PLH}	G 2	A V	2	9	2	7.5	20
^t PHL	92	Any Y	2	10	2	8.5	TIS

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

PARAMETER MEASUREMENT INFORMATION SERIES 54ALS/74ALS AND 54AS/74AS DEVICES



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
- D. All input pulses have the following characteristics: $PRR \le 1$ MHz, $t_f = t_f = 2$ ns, duty cycle = 50%.
- E. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms



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